File   View   Edit   Tools   Window   Help

Active
- L1: (5336) antifuse or anti-fuse or (anti adj fuse)
- L2: (15698) dielectric adj2 (breakdown or break-down or (break adj down))
- L3: (3457) defect$5 adj2 address
- L4: (154) 1 with 2
- L7: (13) 3 and 4
- L9: (78) 1 same 3
- L10: (65) 9 not 7
- L14: (2986) redundan$3 adj control$4
- L15: (6665) program$6 adj element
- L16: (55) 3 same 15
- L18: (58) 14 and 15
- L19: (169) 3 and 15
- L20: (103) 19 not (16 or 18)
- L21: (1532) 365/225.7
- L22: (6619) 365/200
- L23: (1223) 365/96
- L24: (628) 327/525
- L25: (216) 327/526
- L26: (178) 1 and 3
- L27: (240) 20 or 26
- L28: (57) 27 and 21
- L29: (133) 27 and 22
- L30: (25) 27 and 23
- L31: (7) 27 and 24
- L32: (7) 27 and 25
- L33: (27) (FUJIMA near2 SHIRO).in.

Failed

Search List Browse Queen Clear

DBs: US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

Default operator: OR

☑ Purals
☑ Highlight all hit terms initially

BRS form   ISLR form   Image   Text   HTML

	U	☆	⚑	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Cl	Inventor	S	C
1	☐	☑	☐	US 6115283 A	20000905	36	Semiconductor device with programming capacitance elem...	365/149	365/200		Hidaka; Hideto	☑	☐
2	☐	☑	☑	US 6438059 B2	20020820	16	Fuse programming circuit for programming fuses	365/225.7	257/E27.062; 327/525;		Akita; Hironobu et al.	☑	☐
3	☐	☐	☑	US 6163488 A	20001219	31	Semiconductor device with antifuse	365/200	365/225.7; 365/96		Tanizaki; Hiroaki et al.	☑	☐
4	☐	☐	☑	US 6424584 B1	20020723	16	Redundancy antifuse bank for a memory device	365/225.7	365/185.09; 365/185.26;		Seyyedy; Mirmajid	☑	☐

Hits   Details   HTML

Ready   NUM